

Search Notes**Application/Control No.**

10/532,632

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	299	1/2/2008	EB
375	267	1/2/2008	EB
375	150	1/2/2008	EB
375	349	1/2/2008	EB
375	347	1/2/2008	EB
375	295	1/2/2008	EB
375	265	1/2/2008	EB
370	335	1/2/2008	EB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	1/2/2008	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	295	1/2/2008	EB
375	265	1/2/2008	EB